

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Jong Shik YOON et al. Confirmation No.: 8658
Application Number : 10/825,343
Filed : April 15, 2004
Title : MINIMIZING TRANSISTOR VARIATIONS DUE TO SHALLOW
TRENCH ISOLATION STRESS
TC/Art Unit : 2813
Examiner: : Thanh T. Nguyen

Docket No. : TI-37043 (0025.0245)
Customer No. : **23494**

MAIL STOP AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

REPLY TO OFFICE ACTION

OK to ENTER!

TN In reply to the Final Office Action mailed July 22, 2008 and pursuant to the
9/30/08 provisions of 37 C.F.R. § 1.116, Applicants propose to amend the above-identified
application as follows:

Amendments to the Claims are reflected in the listing of claims in this paper.

Remarks/Arguments follow the amendment sections of this paper.